

UNISONIC TECHNOLOGIES CO., LTD

50N06-Q Preliminary Power MOSFET

50A, 60V N-CHANNEL POWER MOSFET

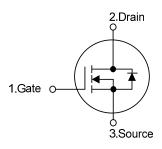
■ DESCRIPTION

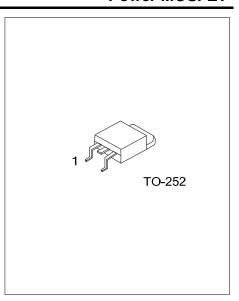
The UTC **50N06-Q** is a high voltage power MOSFET designed to have better characteristics, such as fast switching time, low gate charge, low on-state resistance and high rugged avalanche characteristics. This power MOSFET is usually used in high speed switching applications of switching power supplies and adaptors.

■ FEATURES

- * $R_{DS(ON)} \le 27 \text{ m}\Omega$ @ $V_{GS}=10V$, $I_D=25A$
- * Fast switching capability
- * Avalanche energy tested
- * Improved dv/dt capability, high ruggedness

■ SYMBOL

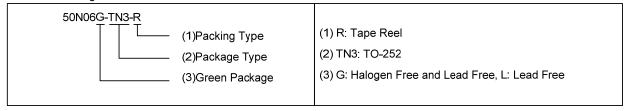




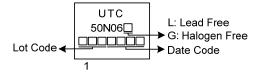
ORDERING INFORMATION

Ordering Number		Dooksas	Pin Assignment			Dooking	
Lead Free	Halogen Free	Package	1	2	3	Packing	
50N06L-TN3-R	50N06G-TN3-R	TO-252	G	D	S	Tape Reel	

Note: Pin Assignment: G: Gate D: Drain S: Source



■ MARKING



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■ ABSOLUTE MAXIMUM RATINGS (T_C = 25°C, unless otherwise specified)

PARAMETER	SYMBOL	RATINGS	UNIT
Drain-Source Voltage	V_{DSS}	60	V
Gate-Source Voltage	V_{GSS}	±20	V
Continuous Drain Current	I_{D}	50	Α
Pulsed Drain Current (Note 2)	I_{DM}	100	Α
Avalanche Energy Single Pulsed (Note 3)	E _{AS}	100.4	mJ
Peak Diode Recovery dv/dt (Note 4)	dv/dt	2.9	V/ns
Power Dissipation	P_{D}	53.5	W
Junction Temperature	T_J	+150	°C
Storage Temperature	T_{STG}	-55 ~ + 150	°C

Notes: 1. Absolute maximum ratings are those values beyond which the device could be permanently damaged.

Absolute maximum ratings are stress ratings only and functional device operation is not implied.

- 2. Repetitive Rating: Pulse width limited by maximum junction temperature.
- 3. L = 0.1mH, I_{AS} = 44.8A, V_{DD} = 50V, R_{G} = 25 Ω , Starting T_{J} = 25°C
- 4. $I_{SD} \le 25A$, di/dt $\le 200A/\mu s$, $V_{DD} \le BV_{DSS}$, Starting $T_J = 25^{\circ}C$

■ THERMAL DATA

PARAMETER	SYMBOL RATINGS		UNIT	
Junction to Ambient	θ_{JA}	110	°C/W	
Junction to Case	θ_{JC}	2.33 (Note)	°C/W	

Note: Device mounted on FR-4 substrate P_C board, 2oz copper, with 1inch square copper plate.

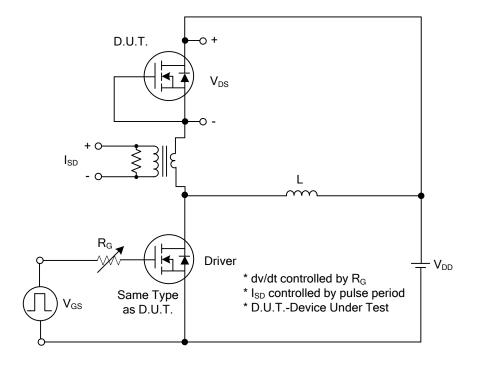
■ **ELECTRICAL CHARACTERISTICS** (T_J =25°C, unless otherwise specified)

PARAMETER	SYMBOL	TEST CONDITIONS	MIN	TYP	MAX	UNIT
OFF CHARACTERISTICS						
Drain-Source Breakdown Voltage	BV _{DSS}	$V_{GS} = 0V, I_D = 250\mu A$	60			V
Drain-Source Leakage Current	I _{DSS}	$V_{DS} = 60V, V_{GS} = 0V$			10	μΑ
Coto Source Leekage Current Forward		$V_{GS} = 20V, V_{DS} = 0V$			100	nA
Gate- Source Leakage Current Reverse	- I _{GSS}	$V_{GS} = -20V, V_{DS} = 0V$			-100	nA
ON CHARACTERISTICS						
Gate Threshold Voltage	$V_{GS(TH)}$	$V_{DS} = V_{GS}, I_{D} = 250 \mu A$	2.0		4.0	V
Static Drain-Source On-State Resistance	R _{DS(ON)}	$V_{GS} = 10V, I_D = 25A$			27	mΩ
DYNAMIC CHARACTERISTICS						
Input Capacitance	C _{ISS}			1293.1		pF
Output Capacitance	C_{OSS}	V _{DS} =25V, V _{GS} =0V, f=1.0MHz		310.5		pF
Reverse Transfer Capacitance	C_{RSS}			26.8		pF
SWITCHING CHARACTERISTICS						
Total Gate Charge (Note 1)	Q_G	\\ -49\\ \\ -10\\ -50A		29.3		nC
Gate-Source Charge	Q_GS	V_{DS} =48V, V_{GS} =10V, I_{D} =50A I_{G} =1mA (Note 1, 2)		8.8		nC
Gate-Drain Charge	Q_GD	IG-IIIIA (Note 1, 2)		6.4		nC
Turn-On Delay Time (Note 1)	$t_{D(ON)}$			7.6		ns
Turn-On Rise Time	t_R	V_{DS} =30V, V_{GS} =10V, I_{D} =50A,		16.3		ns
Turn-Off Delay Time	$t_{D(OFF)}$	R _G =3Ω (Note 1, 2)		21.2		ns
Turn-Off Fall Time	t_{F}			16.4		ns
DRAIN-SOURCE DIODE CHARACTERISTIC	S AND MAX	IMUM RATINGS				
Maximum Continuous Drain-Source Diode	Is				25	Α
Forward Current	IS				20	^
Maximum Pulsed Drain-Source Diode Forwar	d law				100	Α
Current	I _{SM}				100	^
Drain-Source Diode Forward Voltage (Note 1)	V_{SD}	I_S =50A , V_{GS} =0V			1.4	V
Reverse Recovery Time (Note 1)	t _{rr}	I_S =30A , V_{GS} =0V		72		ns
Reverse Recovery Charge	Q_{rr}	di/dt=100A/µs		189		nC

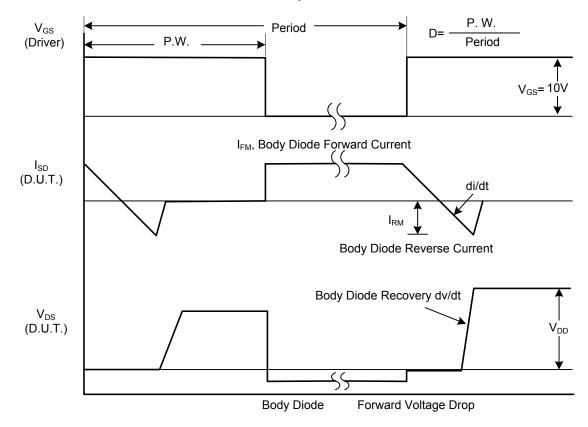
Notes: 1. Pulse Test: Pulse width ≤ 300µs, Duty cycle ≤ 2%.

^{2.} Essentially independent of operating temperature.

■ TEST CIRCUITS AND WAVEFORMS

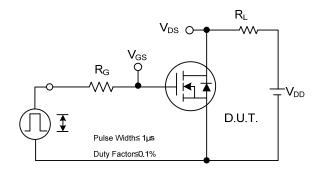


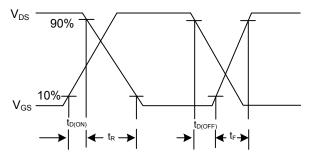
Peak Diode Recovery dv/dt Test Circuit



Peak Diode Recovery dv/dt Waveforms

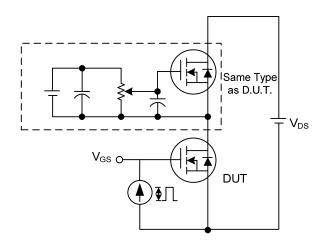
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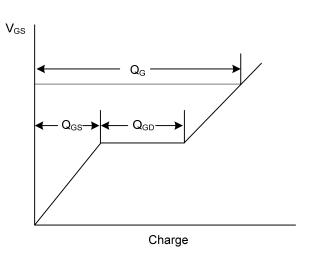




Switching Test Circuit

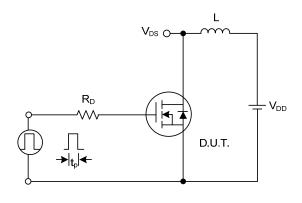
Switching Waveforms

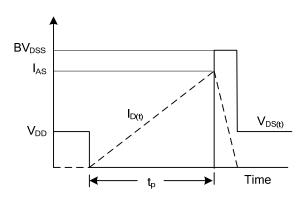




Gate Charge Test Circuit

Gate Charge Waveform





Unclamped Inductive Switching Test Circuit

Unclamped Inductive Switching Waveforms

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